Notice of References Cited	Application/Control No. 10/002,175	Applicant(s)/Patent Under Reexamination BOWEN, NEAL M.	
	Examiner	Art Unit	
	Lynne Edmondson	1725	Page 1 of 1
	J.S. PATENT DOCUMENTS		

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,292,050	03-1994	Nagaoka et al.	228/4.5
	В	US-6,333,562	12-2001	Lin, Chun Hung	257/777
*	С	US-2003/0042621	03-2003	Chen et al.	257/784
*	D	US-6,148,505	11-2000	Fujishima, Mitsushiro	29/740
*	Е	US-2003/0049882	03-2003	Yin et al.	438/106
	F	US-5,269,452	12-1993	Sterczyk, Tim	228/49.2
	G	US-6,629,013	09-2003	Koduri et al.	700/121
	Н	US-6,555,917	04-2003	Heo, Young Wook	257/777
*	ı	US-6,091,140	07-2000	Toh et al.	257/691
*	J	US-5,502,289	03-1996	Takiar et al.	174/266
*	К	US-5,498,767	03-1996	Huddleston et al.	716/12
*	L	US-5,054,194	10-1991	Pollock, Randy	29/840
*	М	US-5,702,049	12-1997	Biggs et al.	228/105

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	Ν	JP-07-202069-A	08-1995	Japan	Kondo	
	0	·				
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.